

Search Notes**Application/Control No.**

08/990,096

Examiner

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Applicant(s)/Patent under Reexamination

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Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
709	223	7/31/2006	HN
	224		
	203		
	218		
	219		
	220		
	225		
	226		
	229		
370	230		
	230.1		
	231		
	468		
	395.41		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	7/31/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner